

**Notice of References Cited**

Application/Control No.

10/577,333

Applicant(s)/Patent Under

Reexamination

YAMADA ET AL.

Examiner

SHANE FANG

Art Unit

1796

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**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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